General Description

FSMOS® MOSFET is based on Oriental Semiconductor's unique device design to achieve low $R_{DS(ON)}$, low gate charge, fast switching and excellent avalanche characteristics. The high V_{th} series is specially designed to use in power supply systems with driving voltage of more than 10V.

Features

- Low $R_{DS(ON)}$ & FOM
- Extremely low switching loss
- Excellent reliability and uniformity
- Fast switching and soft recovery

Applications

- PD charger
- Motor driver
- Switching voltage regulator
- DC-DC convertor
- Switching mode power supply

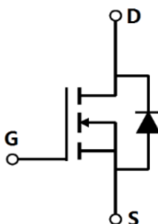
Key Performance Parameters

Parameter	Value	Unit
V_{DS}	100	V
$I_{D, pulse}$	168	A
$R_{DS(ON), max}$ @ V_{GS}=10V	12	mΩ
Q_g	16.4	nC
PD	40	W

Marking Information

Product Name	Package	Marking
SFS10R12FNF	TO220F	SFS10R12FN

Package & Pin information



Oriental Semiconductor © Copyright Reserved V1.0

Absolute Maximum Ratings at T_j=25°C unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	100	V
Gate-source voltage	V_{GS}	±20	V
Continuous drain current[1)], T_C=25 °C	I_D	42	A
Pulsed drain current[2)], T_C=25 °C	$I_{D, pulse}$	168	A
Continuous diode forward current[1)], T_C=25 °C	I_S	42	A
Diode pulsed current[2)], T_C=25 °C	$I_{S, pulse}$	168	A
Power dissipation[3)], T_C=25 °C	P_D	40	W
Single pulsed avalanche energy[4)]	E_{AS}	139	mJ
Operation and storage temperature	T_{stg}, T_j	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case	$R_{θJC}$	3.1	°C/W
Thermal resistance, junction-ambient	$R_{θJA}$	62.5	°C/W

Electrical Characteristics at T_j=25°C unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-source breakdown voltage	BV_{DSS}	100			V	V_{GS}=0 V, I_D=250 μA
Gate threshold voltage	$V_{GS(th)}$	2		4	V	V_{DS}=V_{GS}, I_D=250 μA
Drain-source on-state resistance	$R_{DS(ON)}$		10.7	12	mΩ	V_{GS}=10 V, I_D=30 A
Gate-source leakage current	I_{GSS}			100	nA	V_{GS}=20 V
				-100		V_{GS}=-20 V
Drain-source leakage current	I_{DSS}			1	μA	V_{DS}=100 V, V_{GS}=0 V
Gate resistance	R_G		1.7		Ω	f=1 MHz, Open drain

Oriental Semiconductor © Copyright Reserved V1.0

Dynamic Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Input capacitance	C_{iss}		1198		pF	V_{GS}=0 V, V_{DS}=50 V, *f*=100 kHz
Output capacitance	C_{oss}		349		pF	
Reverse transfer capacitance	C_{rss}		5.9		pF	
Turn-on delay time	$t_{d(on)}$		10		ns	V_{GS}=10 V, V_{DS}=50 V, R_G=2 Ω, I_D=30 A
Rise time	t_r		3.6		ns	
Turn-off delay time	$t_{d(off)}$		14		ns	
Fall time	t_f		4		ns	

Gate Charge Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Total gate charge	Q_g		16.4		nC	V_{GS}=10 V, V_{DS}=50 V, I_D=30 A
Gate-source charge	Q_{gs}		6		nC	
Gate-drain charge	Q_{gd}		3.1		nC	
Gate plateau voltage	$V_{plateau}$		5.3		V	

Body Diode Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Diode forward voltage	V_{SD}			1.1	V	I_S=50 A, V_{GS}=0 V
Reverse recovery time	t_{rr}		33.9		ns	V_R=50 V, I_S=30 A, di/dt=400 A/μs
Reverse recovery charge	Q_{rr}		115		nC	
Peak reverse recovery current	I_{rrm}		5.7		A	

Note

1) Calculated continuous current based on maximum allowable junction temperature.
2) Repetitive rating; pulse width limited by max. junction temperature.
3) Pd is based on max. junction temperature, using junction-case thermal resistance.
4) V_{DD}=50 V,V_{GS}=10 V, L=0.3 mH, starting T_j=25 °C.

Oriental Semiconductor © Copyright Reserved V1.0

Electrical Characteristics Diagrams

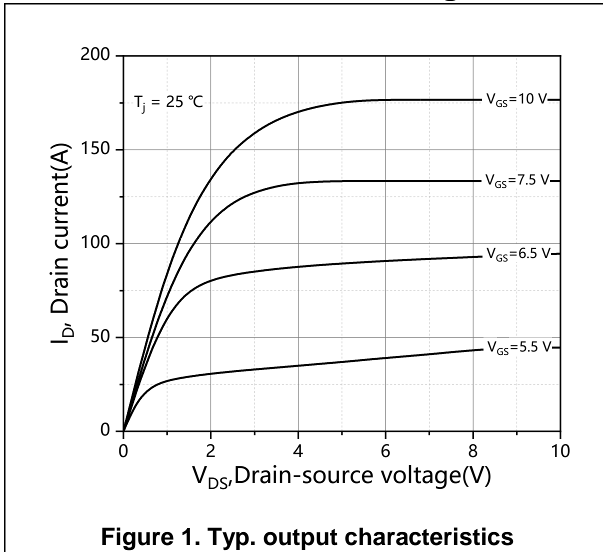


Figure 1. Typ. output characteristics

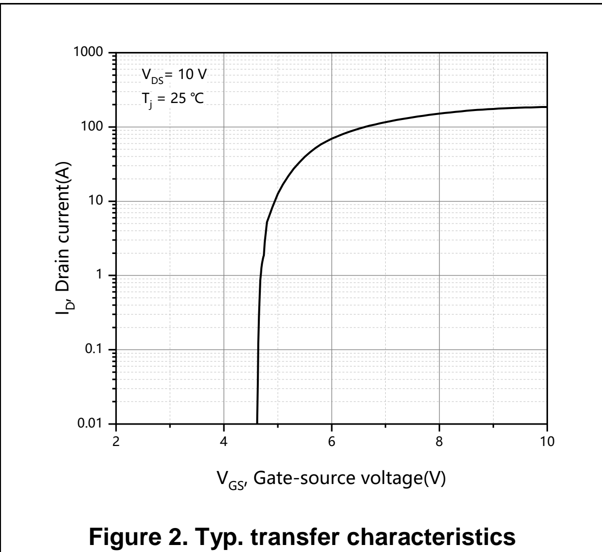


Figure 2. Typ. transfer characteristics

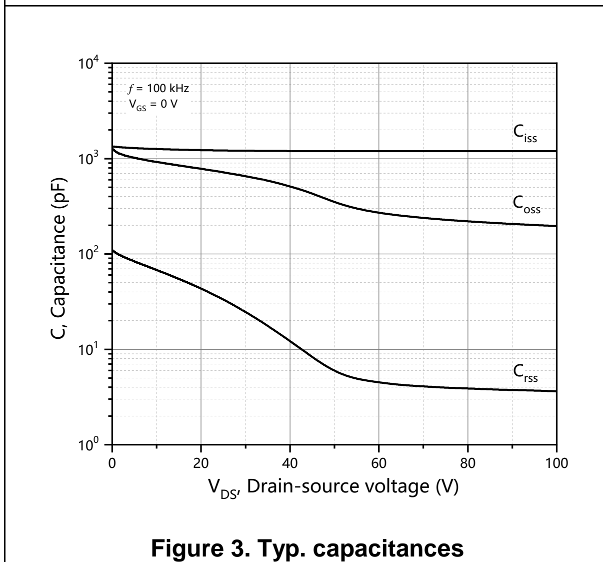


Figure 3. Typ. capacitances

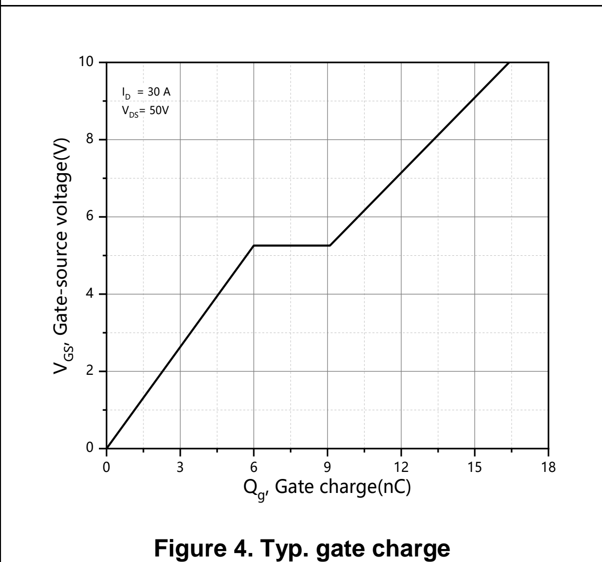


Figure 4. Typ. gate charge

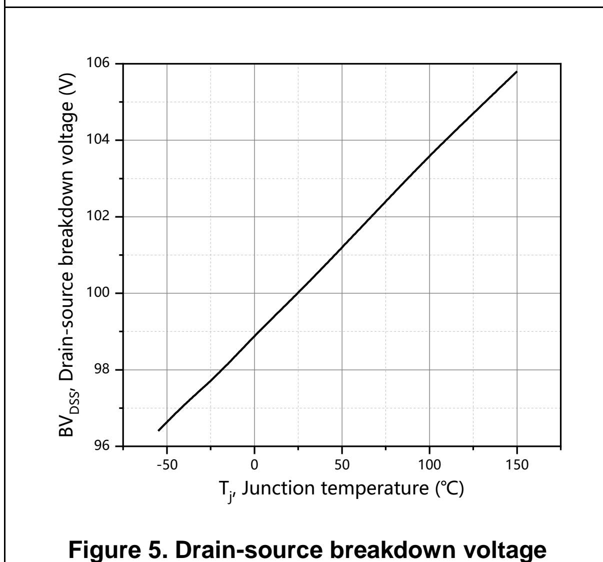


Figure 5. Drain-source breakdown voltage

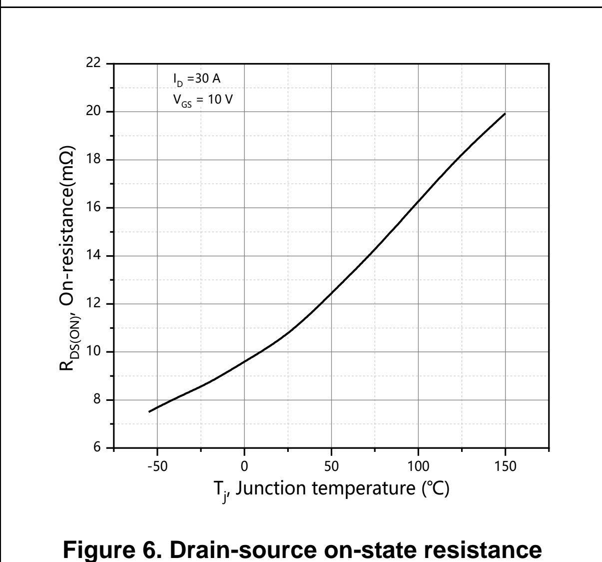


Figure 6. Drain-source on-state resistance

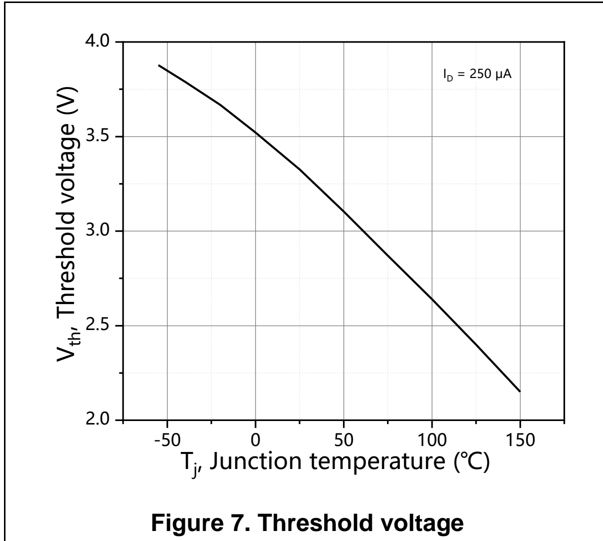


Figure 7. Threshold voltage

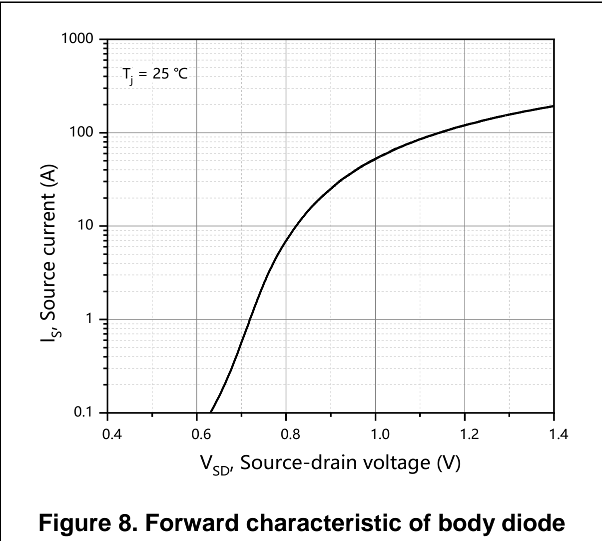


Figure 8. Forward characteristic of body diode

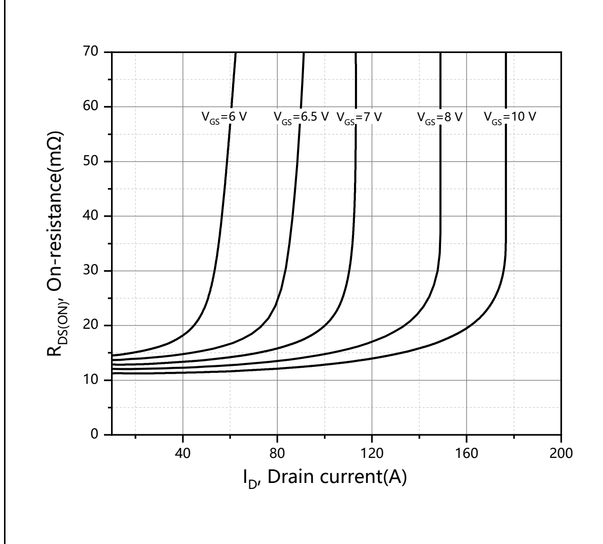


Figure 9. Drain-source on-state resistance

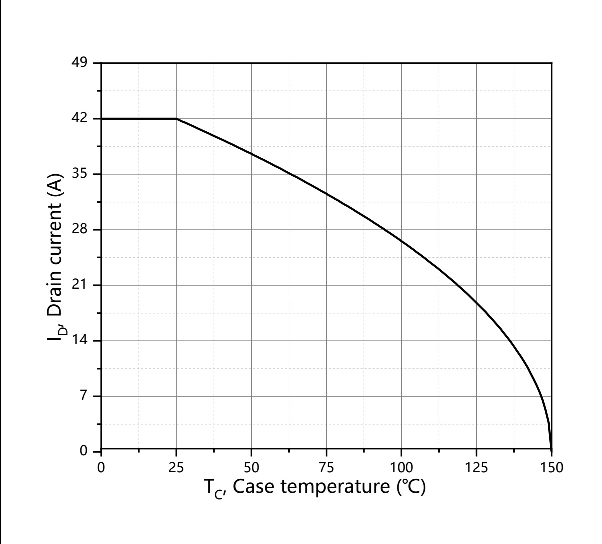


Figure 10. Drain current

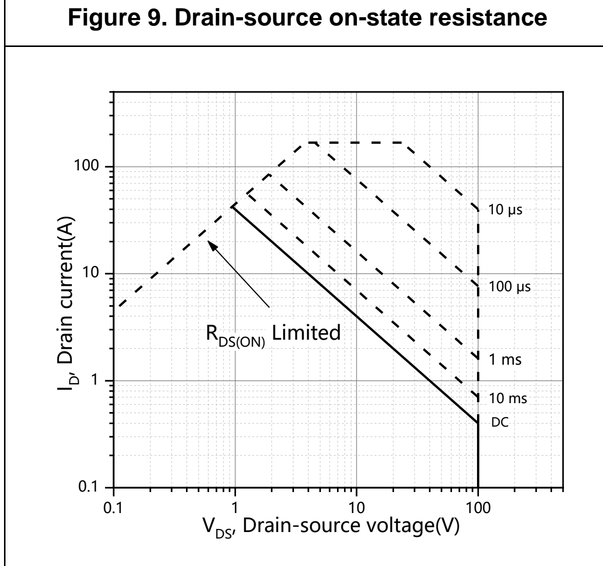


Figure 11. Safe operation area TC=25 ℃

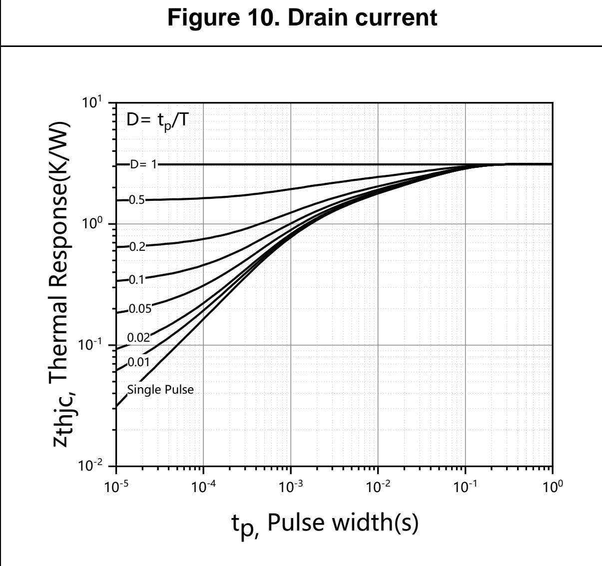


Figure 12. Max. transient thermal impedance

Oriental Semiconductor © Copyright Reserved V1.0

Test circuits and waveforms

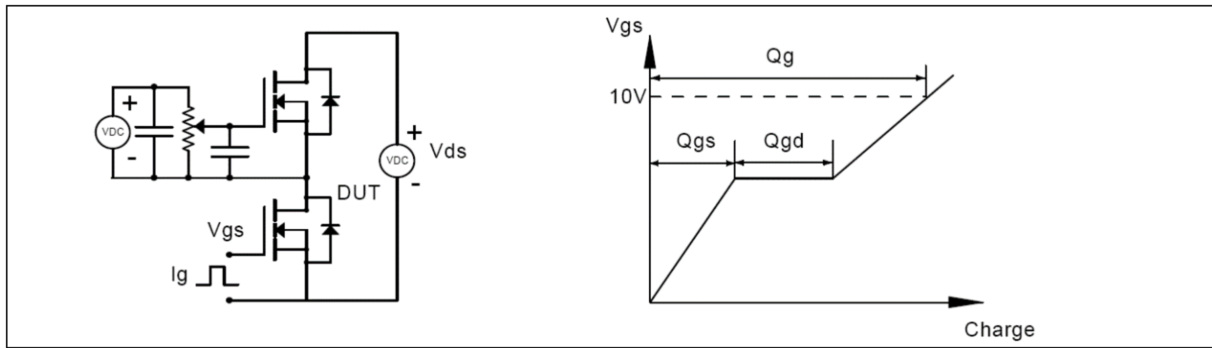


Figure 1. Gate charge test circuit & waveform

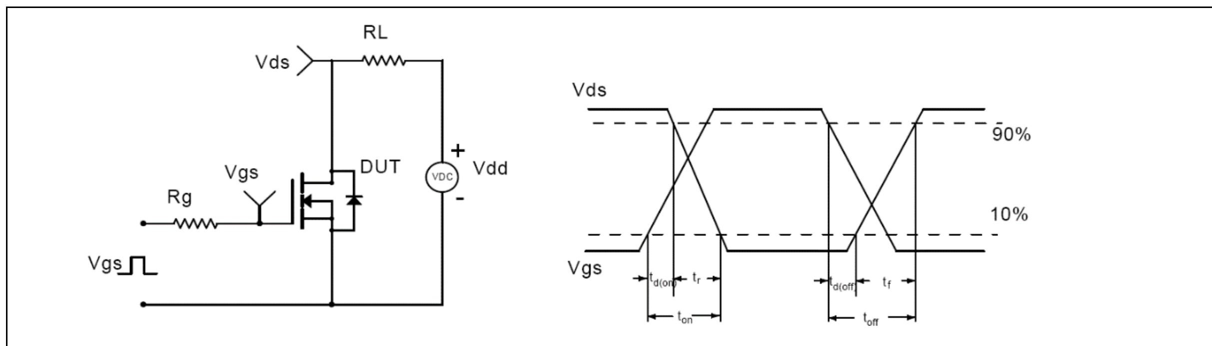


Figure 2. Switching time test circuit & waveforms

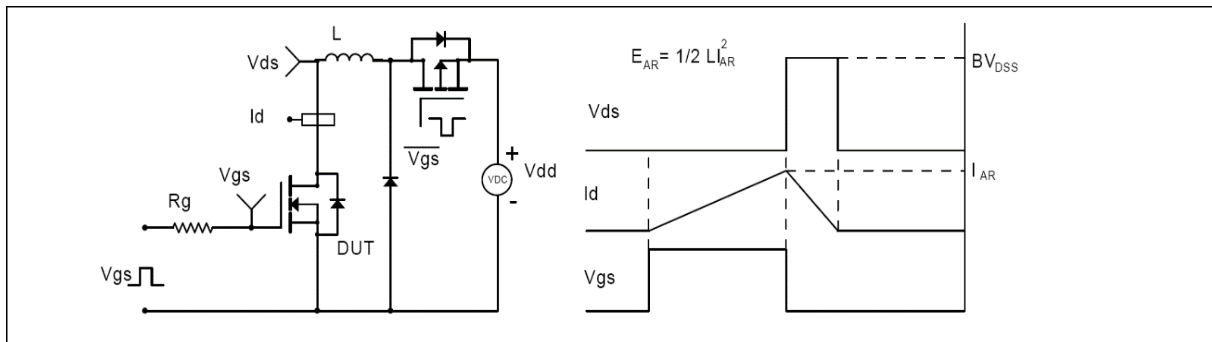


Figure 3. Unclamped inductive switching (UIS) test circuit & waveforms

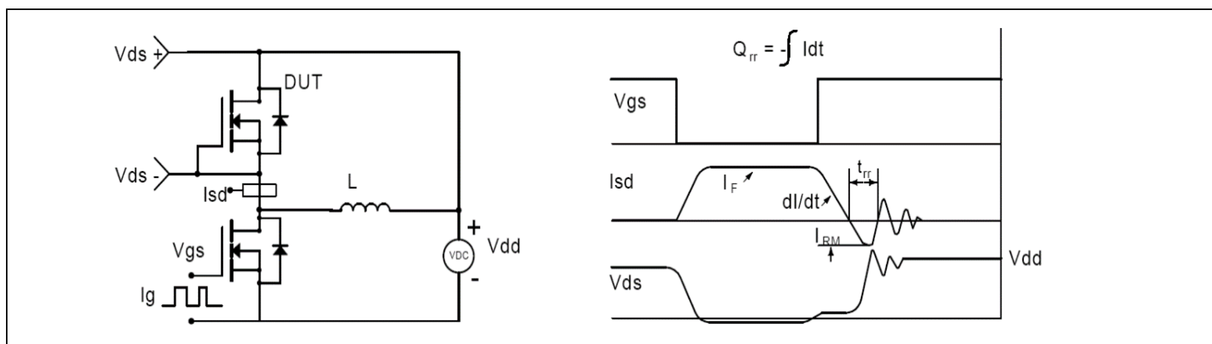
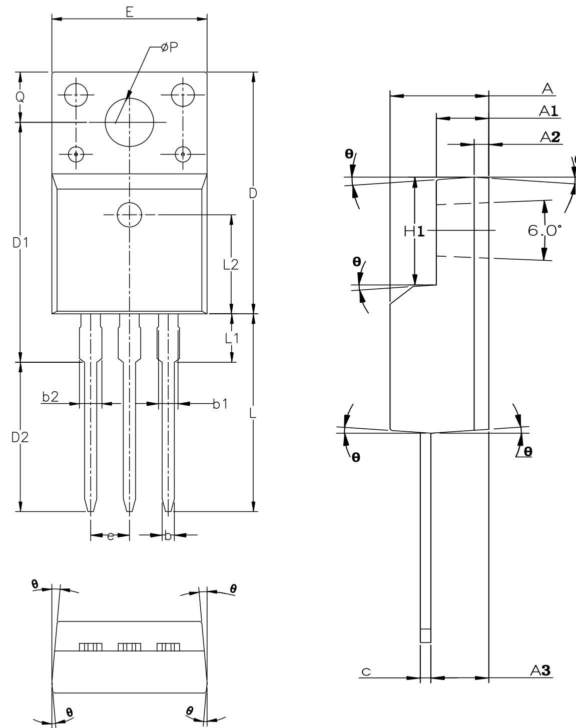


Figure 4. Diode reverse recovery test circuit & waveforms

Package Information



Symbol	mm		
	Min	Nom	Max
A	4.50	4.70	4.83
A1	2.34	2.54	2.74
A2	0.70 REF		
A3	2.56	2.76	2.93
b	0.70	-	0.90
b1	1.18	-	1.38
b2	-	-	1.47
c	0.45	0.50	0.60
D	15.67	15.87	16.07
D1	15.55	15.75	15.95
D2	9.60	9.80	10.00
E	9.96	10.16	10.36
e	2.54 BSC		
H1	6.48	6.68	6.88
L	12.68	12.98	13.28
L1	-	-	3.50
L2	6.50 REF		
ΦP	3.08	3.18	3.28
Q	3.20	-	3.40
θ	1°	3°	5°

Version : TO220F-J package outline dimension

Ordering Information

Package Type	Units/ Tube	Tubes/ Inner Box	Units/ Inner Box	Inner Box/ Carton Box	Units/ Carton Box
TO220F-J	50	20	1000	5	5000

Product Information

Product	Package	Pb Free	RoHS	Halogen Free
SFS10R12FNF	TO220F	yes	yes	yes

Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Oriental Semiconductor hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

For further information on technology, delivery terms and conditions and prices, please contact the Oriental Semiconductor sales representatives (www.orientalsemi.com).

© Oriental Semiconductor Co.,Ltd. All Rights Reserved

Revision History

Version	Revision History	Date
V1.0	Initial release	2025-06-05

ORIENTAL® SEMICONDUCTOR

A Power Semiconductor Innovator